

AMENDMENTS TO THE CLAIMS

(IN FORMAT COMPLIANT WITH THE REVISED 37 CFR 1.121)

1. (CURRENTLY AMENDED) An apparatus comprising:

one or more groups of boundary scan cells;

one or more group buffers coupled to each of said groups
of boundary scan cells;

5 one or more repeater buffers coupled in series with said
group buffers;

a controller coupled to said groups of boundary scan
cells through said group buffers and said repeater buffers, wherein

10 (i) said apparatus is configured to buffer said groups of boundary
scan cells to reflect an order of I/Os around said apparatus and

(ii) said groups of boundary scan cells are routed within an I/O
portion of said apparatus to avoid routing through an interior
portion of said apparatus to keep said interior portion free for
functional routing;

15 one or more flip flops each configured to provide a scan
enable output; and

a scan enable signal configured to control a scan
connection between each of said flip flops.

2. (ORIGINAL) The apparatus according to claim 1,
wherein said groups of boundary scan cells comprise a scan chain.

3. (ORIGINAL) The apparatus according to claim 2, wherein said repeater buffers are configured to eliminate skew at the beginning pins and end pins of the scan chain.

4. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus further comprises:

one or more boundary scan control nets configured to control said groups of boundary scan cells.

5. (CANCELED)

6. (ORIGINAL) The apparatus according to claim 1, wherein each boundary scan cell of said groups of boundary scan cells are implemented within an I/O cell.

7. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus comprises a clock chain in a first direction and a data path in an opposite direction of said first direction.

8. (CANCELED)

9. (CANCELED)

10. (CURRENTLY AMENDED) An apparatus comprising:

means for implementing one or more groups of boundary scan cells;

5 means for implementing one or more group buffers coupled to each one of said groups of boundary scan cells;

means for implementing one or more repeater buffers coupled in series with said group buffers; and

means for controlling coupled to said groups of boundary scan cells through said group buffers and said repeater buffers;

10 means for buffering said groups of boundary scan cells to reflect an order of I/Os around said apparatus, wherein said groups of boundary scan cells are routed within an I/O portion of said apparatus to avoid routing through an interior portion of said apparatus to keep said interior portion free for functional
15 routing;

means for providing a scan enable output; and

means for controlling a scan connection between one or more flip flops.

11. (PREVIOUSLY PRESENTED) A method for optimizing buffers for JTAG boundary scan nets, comprising the steps of:

(A) reading a netlist;

(B) reading an I/O order list;

5 (C) defining a number of I/Os per groups;

- (D) determining if a last I/O is connected;
- (E) writing a final netlist; and
- (F) determining if starting a new group is necessary.

12. (CANCELED)

13. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein step (D) further comprises:
splitting a net.

14. (ORIGINAL) The method according to claim 13, wherein step (D) further comprises:
inserting a repeater buffer.

15. (ORIGINAL) The method according to claim 14, wherein step (D) further comprises:
inserting a group buffer.

16. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein step (D) further comprises:
connecting a next I/O to a newest group buffer.

17. (ORIGINAL) The method according to claim 11, further comprising the following step:

repeating step (D).

18. (ORIGINAL) The method according to claim 11, wherein step (E) further comprises:

buffering said JTAG boundary scan nets to reflect the order of I/O cells around a circuit.

19. (ORIGINAL) The method according to claim 11, wherein steps (E) further comprises:

providing boundary scan cell placement.

20. (ORIGINAL) The method according to claim 11, wherein step (E) further comprises:

allowing optimum results to be obtained automatically.